

Based on application PTO-1449 (3/90)	ATTY. DOCKET NO. 455610-2580.1	SERIAL NO. 10/673,712
	APPLICANT Lawrence SALANT et al.	
	FILING DATE September 29, 2003	GROUP 2117

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6 407 970	06/2002	Verboom, Johannes J.			
	AB	6 853 696	02/2005	Moser et al.			
	AC	4 615 040	09/1986	Mojoli et al.			
	AD	6 812 688	11/2004	Tan et al.			
	AE	2001 0021151	09/2001	Verboom, Johannes et al.			
	AF	6 463 109 B1	10/2002	McCormack et al.			
	AG	6 996 202 B2	02/2006	McCormack et al.			
	AH	2004 0123018 A1	06/2004	Miller et al.			
	AI	2004 0123191 A1	06/2004	Salant et al.			
	AJ	6 922 384 B2	07/2005	Miyashita et al.			
	AK	4 633 465	12/30/86	Fitch et al.			
	AL	5 337 403	08/09/94	Klingman			
	AM	5,654,987	08/05/97	Nakamura			
	AN	5,726,607	03/10/98	Brede et al			
	AO	5,825,825	10/20/98	Altmann et al			
	AP	5,900,755	05/04/99	Toeppen et al			
	AQ	6,215,363	04/10/01	Conta et al			
	AR	6,295,327	09/25/01	Takla			
	AS	6,445,230	09/03/02	Rupp et al			
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
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	AV	4,680,778	07/14/87	Krinock			
	AW	5,943,378	08/24/99	Keba et al			
	AX	6,188,737	02/13/01	Bruce et al			
	AY	5,914,592	06/22/99	Saito			
	AZ	5,789,954	08/04/98	Toeppen et al			
	BA	4,694,244	08/15/87	Whiteside et al			
	BB	6,112,160	08/29/00	Salant et al.			
	BC	4,876,655	10/24/89	Carlton et al.			
	BD	5,180,971	01/19/93	Montijo			
	BE	6,522,122	02/18/03	Watanabe et al.			
	BF	5,432,791	07/11/95	Gancarcik			
	BG	6,539,318	03/25/03	Miller et al.			
	BH	6,356,127	03/12/02	Klipper et al.			
	BI	4,758,963	07/19/88	Gordon et al.			
	BJ	4,843,309	06/27/89	Kareem et al.			
	BK	6,571,186	05/27/03	Ward			
	BL	2003/0163266	08/28/03	Ward et al.			
	BM	6,549,859	04/15/03	Ward			
	BN	5,714,878	02/03/98	Saito et al.			

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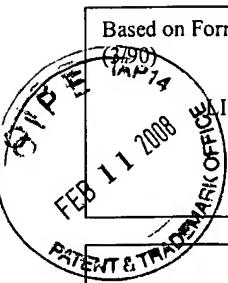
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	BQ	2003/0004664	01/02/03	Ward et al.			
	BR	6,009,132	12/28/99	Sholtz			
	BS	5,978,742	11/02/99	Pirkerd			
	BT	5,761,434	06/02/98	Hewitt			
	BU	5,953,071	09/14/99	Van Zon			
	BV	6,615,148	09/02/03	Pickerd			
	BW	6,642,926	11/04/03	Letts			
	BX	6,044,123	03/28/00	Takla			
	BY	5,999,163	12/07/99	Ivers et al.			
	BZ	5,214,784	05/25/93	Ward et al.			
	CA	5,761,537	06/02/98	Sturges et al.			
	CB	6,311,138	10/30/01	Miller			
	CC	5,402,443	03/28/95	Wong			
	CD	6,643,346	11/04/03	Pedrotti et al.			
	CE	6,546,345	04/08/03	Ghiasi			
	CF	6,278,357	08/21/01	Croushore et al.			
	CG	6,366,631	04/02/02	Nakayama et al.			
	CH	5,966,684	10/12/99	Richardson et al.			
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Lawrence SALANT et al.

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	CL	3 449 671	06/1969	Long Gordon D.			
	CM	3 778 550	12/1973	David et al.			
	CN	4 375 694	03/1983	Kuhn, William B.			
	CO	4 964 117	10/1990	Shier, John S.			
	CP	6 738 992	05/2004	Warwar et al.			
	CQ	2004 0123208	06/2004	Miller et al.			
	CR	2004 0153883	08/2004	Miller et al.			
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	CT	5 305 635 A	04/1994	James et al.			

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	CU	JP4105070	04/07/92	Japan			Abstract
	CV	JP5196641	08/06/93	Japan			Abstract
	CW	JP5264595	10/12/93	Japan			Abstract
	CX	JP8220144	06/22/99	Japan			Abstract
	CY	JP9005362	01/10/97	Japan			Abstract
	CZ	JP10163859	06/19/98	Japan			Abstract
	DA	JP11098876	04/09/99	Japan			Abstract
	DB	JP62003544	01/09/87	Japan			Abstract
	DC	EP 0 631 143	12/28/94	Europe			
	DD	EP 0 241 142	10/14/87	Europe			

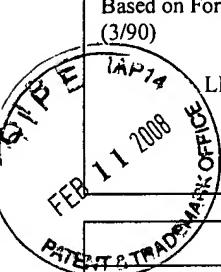
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	DG						
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	DH	EP 0 444 875	09/04/91	Europe			
	DI	EP 1 244 241	09/25/02	Europe			
	DJ	EP 1 074 845	02/07/01	Europe			
	DK	EP 1 118 866	07/25/01	Europe			
	DL	WO 00/60806	10/12/00	PCT			
	DM	DE 2462046 A1	11/1975	Germany			
	DN	WO 2004 032049 A2	04/2004	PCT			
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	DO	Roland E. Best, <i>The Software PLL, Phase Locked Loops</i> , 3 <sup>rd</sup> Edition, McGraw-Hill, New York, 1997, pp 229-249					
	DP	<i>Using FPGAs for Digital Applications</i> , Actel Corporation, April 1996					
	DQ	HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999					
	DR	Infinium DCA, Agilent Technologies, March 7, 2002					
	DS	Communication waveform measurements, Hewlett Packard, June 26, 1996					
	DT	Advanced Analysis of High-Speed Digital Communication Waveforms, Hewlett Packard, June 27, 1994					
	DU	R.E. Anderson and E. M. Foster, Design of an MPEG-2 Transport Demultiplexor Core, IBM, 1999					
	DV	Technology Standards, Tektronix Website ( <a href="http://www.tek.com/Measurement/Solutions/tech_standards/index.html?wt=257">www.tek.com/Measurement/Solutions/tech_standards/index.html?wt=257</a> )					
	DW	Communications Signal Analyzer, Tektronix Website ( <a href="http://www.tektronix.com/optical">www.tektronix.com/optical</a> )					
	DX	RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix Website ( <a href="http://www.Tektronix.com/accessories">www.Tektronix.com/accessories</a> )					
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FOREIGN PATENT DOCUMENTS							
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	EA						
	EB						
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
	EC		Design of FIR Filters by Windowing, MIT Website, ( <a href="http://web.mit.edu/6.555/www/fir.html">http://web.mit.edu/6.555/www/fir.html</a> )				
	ED		A New Digital PLL at the Technische Universitaet Berlin, Technische Universitaet Berlin Website ( <a href="http://www.tdl.com/~gottsch/tuberlin.htm">www.tdl.com/~gottsch/tuberlin.htm</a> )				
	EE		Low Jitter Digital PLL – ZL30407, Zarlink Semiconductor Website, ( <a href="http://products.zarlink.com/product_portlets/new_timer.htm">http://products.zarlink.com/product_portlets/new_timer.htm</a> )				
	EF		Michael K. Williams, et al., A Discussion of Methods for Measuring Low-Amplitude Jitter, International Test Conference, Paper 28.1, pp 646-652				
	EG		Russ Brown, Quantam Corporation, "Eye Diagram Data", SCSI Physical Working Group, February 9, 2000				
	EH		Dave Fink, Tektronix "Introduction to Measurement Techniques and Analysis of Emerging Serial Data Standards", November 2002				
	EI		"Methodologies for Jitter Specification Technical Report" Rev 10, June 9, 1999				
	EJ		Andy Baldwin, University of New Hampshire "Description of XAUI Physical Layer Measurements Performed At The UNH Interoperability Lab", October 30, 2002				
	EK		University of New Hampshire Technical Document, "fast Ethernet" February 13, 2003				
	EL		Dennis Derickson, "Fiber Optic Test and Measurement (Chapter 8); Prentice Hall PTR, 1998, pps. 284-338				
	EM		Adam Healey et al., "Fast Ethernet Consortium - 100 Base-TX PMD Test Suite", Version 2.4 and Version 2.5; InterOperability Lab, 1998-1999				
	EN		Adam Healey, "Fast Ethernet Consortium Notebook", 1996-1997 14 pps.				
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